

University of Notre Dame
College of Science
Department of Physics

NUCLEAR SEMINAR

The Electron Beam Ion Trap-Source: Concept and Research Applications

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***Tuesday, October 26, 2010 4:00 p.m. NSH 124**
(Refreshments will be served prior to the seminar in 124 NSH)

***NOTE DIFFERENT DAY**

The features and operating conditions of the cryogenic "Electron Beam Ion Trap Source (EBIT-S) together with the development and performance of the EBIT-S are reviewed. The fundamental processes that limit the quality and quantity of ion that can be extracted from an EBIT-S are discussed. Various applications of basic as well as applied physics studies of highly charged ions with matter are presented..

ALL INTERESTED PERSONS ARE CORDIALLY INVITED TO ATTEND

10/15/2010 8:58 AM